

A SEM image of talc particles with color added. Rachel Rose, an [MVA Scientific Consultants](#) intern, saw the "stocking" potential, and submitted it during one of the MVA's annual Christmas card contests.

New USC Nano-Imaging Center Opens

A new facility with the latest scanning electron microscopes will position USC to become a national leader in nanoscience and energy.



Dr. Byungmin Ahn, a Center for Nano-Imaging post-doctoral researcher, left, stands next to the MultiBeam FIB. Viterbi School Prof. Steve Nutt, director of the M.C. Gill Foundation Composites Center, is on the right.

A new USC Nano-Imaging Center has opened on the University Park Campus for scientists and engineers probing the mysteries of nanoscale materials and systems.

The center, which was unveiled Dec. 11 at a special symposium, houses three new scanning electron microscopes (SEMs). These instruments will allow researchers from a broad range of the biological and physical sciences to gain a better understanding of nano-materials using the latest, most sophisticated 3-D imaging technology available.

Creation of the new center, a core lab operated jointly by the Viterbi School and the College, is located in the engineering school's Center for Electron Microscopy and Microanalysis. The facility represents an important investment to strengthen USC's research infrastructure and position the university as a national leader in nano-imaging, nano-analysis and nano-fabrication, said Dennis J. Atkinson, director of Corporate Research Advancement. [Read the full announcement >>>](#)

See Us in 2009!

Upcoming Meetings and
Tradeshows

TMS

**The Materials
Society**
Booth #532
San Francisco, CA
Feb 16-18, 2009

AAFS

**American
Academy of
Forensic Sciences**
Booth #400/402
Denver, CO
Feb 18-20, 2009

Advanced Lithography

**San Jose, CA
Feb 23-27, 2009**

Pittcon

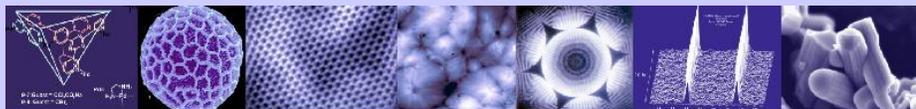
**Booth #3948/4048
Chicago, IL
Mar 9-12, 2009**

JEOL USA in the News

[1st Atomic Scale
Compositional Images of
Fuel Cell Nanoparticles
\(Univ. Texas at Austin\)](#)

[Hi-res Snapshot of
Transformation of
Nanoscale Structures \(LLNL\)](#)

[From Melamine to Cocaine,
They See it All](#)



Microscopy Seminar at University of Southern California



"The Changing World of Electron Microscopy" seminar was hosted by the University of Southern California in conjunction with the opening of the new USC Nano Imaging Center. The seminar, run by JEOL USA and EDAX, Inc., was one the 2008 series of workshops JEOL has held throughout the U.S. this year.

Over 60 people from local industry and academia attended this workshop that highlighted recent developments in electron microscopy. Companies represented at this conference varied from aerospace to automotive to semiconductor. In addition to talks from EDAX and JEOL, Dr. Brendan Foran from the Aerospace Corporation presented electron tomography data from the JEM-3100F. This work reflected the challenges associated with decreasing design rules in the semiconductor field as well as the innovative approaches that are being used to solve these problems.

The symposium concluded with a tour of the new Nano Imaging Facility that recently opened at USC. JEOL USA Inc. recently installed the 4500 multibeam as well as the 6610 SEM and 7001 field emission SEM.

One more seminar in the series is scheduled for January in the Philadelphia area.

If you are interested in upcoming seminars for 2009 and would like to receive announcements or have ideas for future topics, let us know at jeolink@jeol.com.

Quick Links

[JEOL News Magazine](#)

July 2008 - Volume 43 (Note: requires online registration to download).

[Invitation to the SEM World](#)

[Energy Table for EDS Analysis](#)

[A Guide to Scanning Microscope Observation](#)

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JEOL SEM Service & Support News



JEOL USA welcomes a new member of the

SEM product support group. M. Kondo has just joined us from JEOL headquarters in Japan, and brings our total number of combined years of the SEM product group's experience to about 110! The photo shows just four members of our SEM product support team: M. Kondo (foreground), K. Murata (far left), Pat Ritchie (back desk), and Y. Nishida (right). M. Kondo is the newest JEOL employee, having worked in final test in Japan for eight years. While he also has experience with wafer inspection systems, he now specializes in Field Emission SEMs.

The JEOL SEM product support team provides phone support and factory liaison to JEOL's extensive [field service](#) support group throughout the U.S., Mexico, and Canada. They are indeed an important resource for our over 200 engineers in the field, who in turn help our customers with all their SEM needs.

JEOL USA's service department is geared up to install several new FE SEMs this year. The first North American installation of the new [JSM-7600F](#) took place in Canada, and the first U.S. installation was in the Florida panhandle. The Florida-based service engineer was able to complete the installation in good time without help from the Service Support Group. The engineer had been trained at the company's headquarters in Japan prior to the installation. A number of these models will be installed in the western hemisphere early in the new year.

Training of JEOL USA service engineers in all SEM products has been increased recently, with three full time training personnel now working throughout the U.S.